

<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE STATEMENT</b>		DOCKET NUMBER 102155-200		SERIAL NUMBER <del>N/A</del> 10/017,863		
		APPLICANT Szuchain F. Chen, et al.				
		FILING DATE <del>N/A</del> 12/12/01		GROUP ART UNIT 1775		
U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPR.
RRK	3,193,484	07/06/65	Gleim	204	79	
RRK	3,666,637	05/30/72	MacKay	204	30	
RRK	4,234,395	11/18/80	Berdan et al.	204	12	
RRK	4,323,632	04/06/82	Berdan et al.	428	626	
RRK	4,952,531	08/28/90	Cherukuri	501	69	
RRK	5,022,968	06/11/91	Lin et al.	204	28	
RRK	5,098,796	03/24/92	Lin et al.	428	607	
RRK	5,230,932	07/27/93	Chen et al.	428	607	
RRK	5,250,363	10/05/93	Chen	428	607	
RRK	5,449,951	09/12/95	Parthasarathi et al.	257	677	
RRK	5,573,845	11/12/96	Parthasarathi et al.	428	306.6	
RRK	5,658,869	08/19/97	Singer	510	272	
FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
					YES	NO
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						
RRK	"Metallization Contamination," Microelectronic Defects Database, CALCE Electronic Products and Systems Center, University of Maryland, April 12, 2000.					
RRK	Barnes and Robinson, "The Impact of Ionic Impurities in Die Attach Adhesives on Device Performance", Proc. Of 34 <sup>th</sup> Electronics Components Conf., May, 1984, p. 68					
EXAMINER:	Robert R. Koehle			DATE CONSIDERED:	February 22, 2004	

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U.S. PATENT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPR.	
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION		
					YES	NO	
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)							
RRR	Lee, C., et al., "An Analytical Characterization and Reliability Testing of an Adhesion Enhancing Zn-Cr Leadframe Coating for Popcorn Prevention", Conference Preprint, 1998, 9 pages, (no month given).						
EXAMINER:				DATE CONSIDERED:			
Robert R. Koehler				February 22, 2004			

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			FILING DATE December 12, 2001		GROUP ART UNIT <del>1762</del> 1775	
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FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
					YES	NO
<i>BBK</i>	JP 55-44536	3/1980	Japan	C21D 9/48	<i>abs.</i>	X
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						
<i>BBK</i>	International Search Report for PCT/US01/50660, filing date December 20, 2001					
EXAMINER: <i>Robert R. Koehle</i>				DATE CONSIDERED: <i>February 22, 2004</i>		

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